

Notice of References Cited	Application/Control No. 10/604,409		Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Nathan W. Ha		Art Unit 2814	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0096754 A1	07-2002	Chen et al.	257/686
	B	US-2003/0127722 A1	07-2003	Nakaoka et al.	257/686
	C	US-6,737,755 B1	05-2004	McLellan et al.	257/796
	D	US-6,555,917 B1	04-2003	Heo, Young Wook	257/777
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.